

Contents

Chinese Abstract	i
English Abstract	ii
Acknowledgment	iv
Contents	vi
Table Captions	vii
Figure Captions	viii
Chapter 1. Introduction	1
1-1 LTPS TFT	1
1-2 Variation	2
1-3 Reliability	4
Chapter 2. Stress Mapping for Reliability	9
2-1 Experiment	9
2-1-1 Device Fabrication	9
2-1-2 Method of Device Parameters Extraction	9
2-1-2-1. Determination of the Threshold Voltage	10
2-1-2-2. Determination of the Sub-threshold Swing	10
2-1-2-3. Determination of the Field-effect Mobility	11
2-1-3 Degradation Behavior Brief	12
2-1-4 Grids of Stress Map	13
2-2 Results and Discussion	14
2-2-1 Threshold Voltage (V_t , V_t^*) Shift and Negative V_t , V_t^* shift ..	14
2-2-2 I_{on} , I_{on}^* Degradation Rate and I_{on} , I_{on}^* Increase Rate	15
2-2-3 Mobility Degradation Rate and Mobility Increase Rate	16
2-2-4 Sub-threshold Swing (S.S) Variation and S.S [*] variation	17
2-3. Discussion	18
2-4. Conclusion	20
Chapter 3. Diverse Degradation Behaviors	34
3-1 Experiment	34
3-2 Results and Discussion	34
3-3 Conclusion	35
Chapter 4. Initial Characteristic Dependence	69
4-1 Experiment	69
4-2 Results and Discussion	69
4-3 Conclusion	72
Chapter 5. Conclusion	77
References	79